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THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Lu et al.
Appl. No. : 10/811,153
Filed : March 29, 2004
Title : LIGHT-EMITTING DEVICES WITH FULLERENE LAYERS

Grp./A.U. :
Examiner :

Docket No.: 14657

Honorable Assistant Commissioner of Patents
Alexandria, VA 22313-1450

Sir:

PTO CUSTOMER NO. 000293

INFORMATION DISCLOSURE STATEMENT

In accordance with 37 C.F.R., §§ 1.97-1.99, applicant submits the following information which may be of interest to the examiner in charge of the above referenced application for patent. Only copies of the non-US references listed on the attached Form PTO-1449 are attached.

Respectfully submitted,

DOWELL & DOWELL, P. C.

Ralph A. Dowell, Reg. No.: 26,868

Date: August 9, 2004

DOWELL & DOWELL, P.C.
Suite 309, 1215 Jefferson Davis Highway
Arlington, Virginia 22202
Telephone: (703) 415-2555

FORM PTO-1449
(Rev. 7-80)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

Atty. Docket No. 14657

Serial No.
10/811,153**LIST OF PRIOR ART CITED BY APPLICANT**

(Use several sheets if necessary)

APPLICANT Lu et al.

FILING DATE 03/29/2004

GROUP

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER							DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	5	8	6	1	2	1	9	01/19/99				
	AB	5	7	5	9	7	2	5	06/02/98				
	AC	5	7	7	6	6	2	2	07/07/98				
	AD	6	5	1	5	2	9	8	02/04/03				
	AE	6	4	8	6	6	0	1	11/26/02				
	AF	6	3	1	0	3	6	0	10/30/01				
	AG	2002/0093006							07/18/02				
	AH	2003/0042846							03/06/03				
	AI	4	3	5	6	4	2	9	10/26/82				
	AJ	5	1	7	1	3	7	3	12/15/92				
	AK												

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER							DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
													YES	NO
	AL													
	AM													
	AN													
	AO													

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

	AP		"Metal/AlQ ₃ Interface Structures", Turak et al. Applied Physics Letters, July 22, 2002, Vol. 81(4), pp 766-768.
	AQ		"Organic Light-Emitting Diodes with a Nanostructured Fullerene Layer at the Interface between Alq ₃ and TPD Layers", Kato et al.; Jpn. J. Appl Phys, April 2003, Vol. 42(2003), pp 2526-2529.

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 602; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.